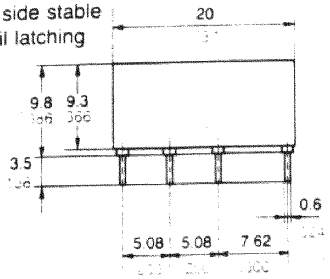
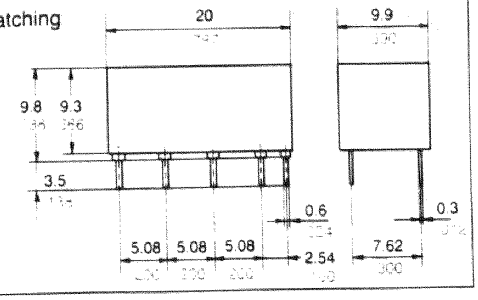
2 Form C

General tolerance: ±0.3 ± .012

Single side stable & 1 coil latching



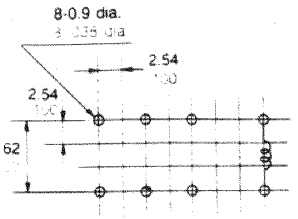
2 coil latching



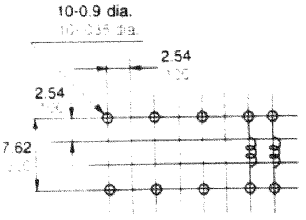
PC board pattern (Copper-side view)

Tolerance: ±0.1 ± .004

Single side stable & 1 coil latching



2 coil latching



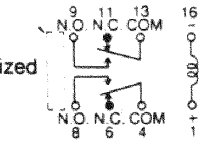
matching 16 pin IC socket

Schematic (Bottom view)

• A polarity bar showing the relay direction can replace the schematic.

Single side stable

Deenergized condition



1 coil latching

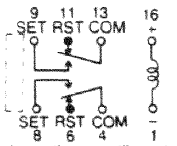


Diagram shows the "reset" position when terminals 1 and 16 are energized. Energize with reverse polarity to transfer contacts.

2 coil latching

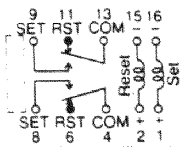


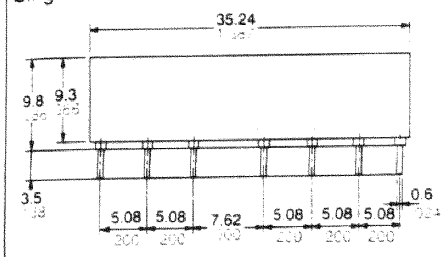
Diagram shows the "reset" position when terminals 2 and 15 are energized. Energize terminals 1 and 16 to transfer contacts.

mm inch

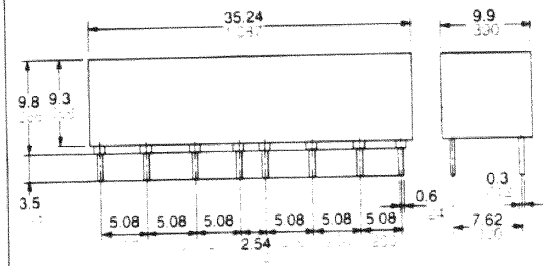
4 Form C

General tolerance: ±0.3 ± .012

Single side stable & 1 coil latching



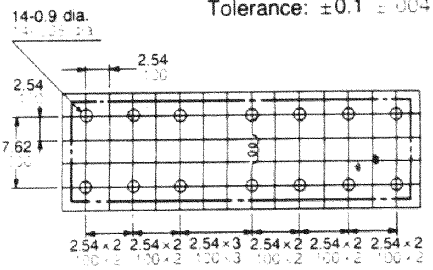
2 coil latching



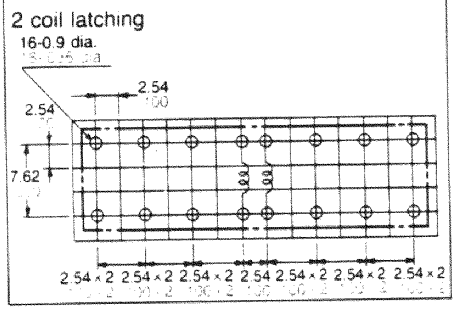
PC board pattern (Copper-side view)

Single side stable & 1 coil latching

Tolerance: ±0.1 ± .004



2 coil latching

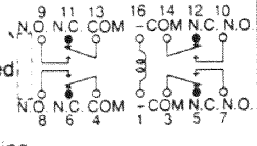


Schematic (Bottom view)

• A polarity bar showing the relay direction can replace the schematic.

Single side stable

Deenergized condition



1 coil latching

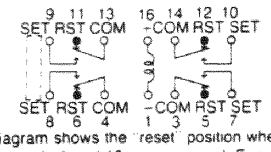


Diagram shows the "reset" position when terminals 1 and 16 are energized. Energize with reverse polarity to transfer contacts.

2 coil latching

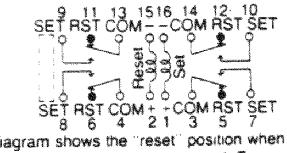


Diagram shows the "reset" position when terminals 2 and 15 are energized. Energize terminals 1 and 16 to transfer contacts.

OPERATING PRINCIPLE - 4 Form C

DS4 (Single side stable)

Fig. 1 Deenergized position

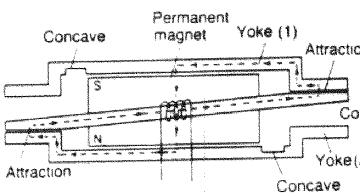


Fig. 2 Energized position

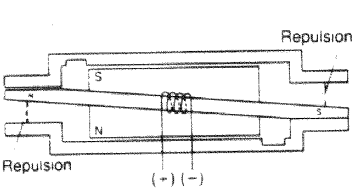


Fig. 1 shows the deenergized position of single side stable versions. Concaves both in yoke (1) and yoke (2) create an unbalance of the magnetic circuit. Therefore the armature is attracted to the yoke (1) and yoke (2) as shown due to the magnetic flux of the permanent magnet.

Energized condition is illustrated in Fig. 2. When the armature is energized as shown, the magnetic repulsion-attraction between the yokes takes place rotating the armature. When the power is removed from the coil, contacts return to the original stage as shown in Fig. 1.

CONSTRUCTION - 4 Form C

Maximum reliability in a high density simplified design